



Welcome to **E-XFL.COM**

Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

| Details | |
|--------------------------------|--|
| Product Status | Obsolete |
| Number of LABs/CLBs | 1176 |
| Number of Logic Elements/Cells | 5292 |
| Total RAM Bits | 57344 |
| Number of I/O | 176 |
| Number of Gates | 236666 |
| Voltage - Supply | 2.375V ~ 2.625V |
| Mounting Type | Surface Mount |
| Operating Temperature | 0°C ~ 85°C (TJ) |
| Package / Case | 256-BGA |
| Supplier Device Package | 256-FBGA (17x17) |
| Purchase URL | https://www.e-xfl.com/product-detail/xilinx/xcv200-5fg256c |

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



General Purpose Routing

Most Virtex signals are routed on the general purpose routing, and consequently, the majority of interconnect resources are associated with this level of the routing hierarchy. The general routing resources are located in horizontal and vertical routing channels associated with the rows and columns CLBs. The general-purpose routing resources are listed below.

- Adjacent to each CLB is a General Routing Matrix (GRM). The GRM is the switch matrix through which horizontal and vertical routing resources connect, and is also the means by which the CLB gains access to the general purpose routing.
- 24 single-length lines route GRM signals to adjacent GRMs in each of the four directions.
- 12 buffered Hex lines route GRM signals to another GRMs six-blocks away in each one of the four directions. Organized in a staggered pattern, Hex lines can be driven only at their endpoints. Hex-line signals can be accessed either at the endpoints or at the midpoint (three blocks from the source). One third of the Hex lines are bidirectional, while the remaining ones are uni-directional.

 12 Longlines are buffered, bidirectional wires that distribute signals across the device quickly and efficiently. Vertical Longlines span the full height of the device, and horizontal ones span the full width of the device.

I/O Routing

Virtex devices have additional routing resources around their periphery that form an interface between the CLB array and the IOBs. This additional routing, called the VersaRing, facilitates pin-swapping and pin-locking, such that logic redesigns can adapt to existing PCB layouts. Time-to-market is reduced, since PCBs and other system components can be manufactured while the logic design is still in progress.

Dedicated Routing

Some classes of signal require dedicated routing resources to maximize performance. In the Virtex architecture, dedicated routing resources are provided for two classes of signal.

- Horizontal routing resources are provided for on-chip 3-state busses. Four partitionable bus lines are provided per CLB row, permitting multiple busses within a row, as shown in Figure 8.
- Two dedicated nets per CLB propagate carry signals vertically to the adjacent CLB.

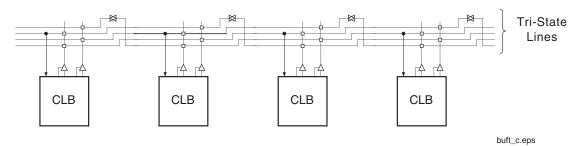


Figure 8: BUFT Connections to Dedicated Horizontal Bus Lines

Global Routing

Global Routing resources distribute clocks and other signals with very high fanout throughout the device. Virtex devices include two tiers of global routing resources referred to as primary global and secondary local clock routing resources.

• The primary global routing resources are four dedicated global nets with dedicated input pins that are designed to distribute high-fanout clock signals with minimal skew. Each global clock net can drive all CLB, IOB, and block RAM clock pins. The primary global nets can only be driven by global buffers. There are four global buffers, one for each global net. The secondary local clock routing resources consist of 24 backbone lines, 12 across the top of the chip and 12 across bottom. From these lines, up to 12 unique signals per column can be distributed via the 12 longlines in the column. These secondary resources are more flexible than the primary resources since they are not restricted to routing only to clock pins.

Clock Distribution

Virtex provides high-speed, low-skew clock distribution through the primary global routing resources described above. A typical clock distribution net is shown in Figure 9.

Four global buffers are provided, two at the top center of the device and two at the bottom center. These drive the four primary global nets that in turn drive any clock pin.



Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is

selected either from these pads or from signals in the general purpose routing.

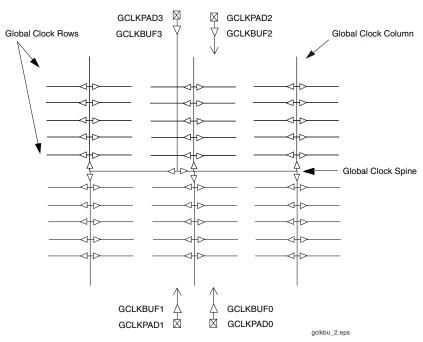


Figure 9: Global Clock Distribution Network

Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks. The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

Boundary Scan

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device.The TAP uses dedicated package pins that always operate using LVTTL. For TDO to operate using LVTTL, the $\rm V_{CCO}$ for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and $\rm V_{CCO}$.

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.

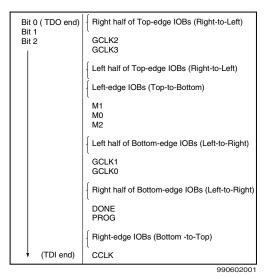


Figure 11: Boundary Scan Bit Sequence

Table 5: Boundary Scan Instructions

| Boundary-Scan Command | Binary Code(4:0) | Description |
|--------------------------|---------------------|--|
| EXTEST | 00000 | Enables boundary-scan EXTEST operation |
| SAMPLE/PRELOAD | 00001 | Enables boundary-scan SAMPLE/PRELOAD operation |
| USER 1 | 00010 | Access user-defined register 1 |
| USER 2 | 00011 | Access user-defined register 2 |
| CFG_OUT | 00100 | Access the configuration bus for read operations. |
| CFG_IN | 00101 | Access the configuration bus for write operations. |
| INTEST | 00111 | Enables boundary-scan INTEST operation |
| USERCODE | 01000 | Enables shifting out USER code |
| IDCODE | 01001 | Enables shifting out of ID Code |
| HIGHZ | 01010 | 3-states output pins while enabling the Bypass Register |
| JSTART | 01100 | Clock the start-up sequence when StartupClk is TCK |
| BYPASS | 11111 | Enables BYPASS |
| RESERVED | All other codes | Xilinx reserved instructions |

Identification Registers

The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined.

The IDCODE register has the following binary format:

vvvv:ffff:fffa:aaaa:aaaa:cccc:cccc1

where

v = the die version number

f = the family code (03h for Virtex family)

a = the number of CLB rows (ranges from 010h for XCV50 to 040h for XCV1000)

c = the company code (49h for Xilinx)

The USERCODE register is supported. By using the USER-CODE, a user-programmable identification code can be loaded and shifted out for examination. The identification code is embedded in the bitstream during bitstream generation and is valid only after configuration.

Table 6: IDCODEs Assigned to Virtex FPGAs

| FPGA | IDCODE |
|---------|-----------|
| XCV50 | v0610093h |
| XCV100 | v0614093h |
| XCV150 | v0618093h |
| XCV200 | v061C093h |
| XCV300 | v0620093h |
| XCV400 | v0628093h |
| XCV600 | v0630093h |
| XCV800 | v0638093h |
| XCV1000 | v0640093h |

Including Boundary Scan in a Design

Since the boundary scan pins are dedicated, no special element needs to be added to the design unless an internal data register (USER1 or USER2) is desired.

If an internal data register is used, insert the boundary scan symbol and connect the necessary pins as appropriate.

Development System

Virtex FPGAs are supported by the Xilinx Foundation and Alliance CAE tools. The basic methodology for Virtex design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing design-



ers with a common user interface regardless of their choice of entry and verification tools. The XDM software simplifies the selection of implementation options with pull-down menus and on-line help.

Application programs ranging from schematic capture to Placement and Routing (PAR) can be accessed through the XDM software. The program command sequence is generated prior to execution, and stored for documentation.

Several advanced software features facilitate Virtex design. RPMs, for example, are schematic-based macros with relative location constraints to guide their placement. They help ensure optimal implementation of common functions.

For HDL design entry, the Xilinx FPGA Foundation development system provides interfaces to the following synthesis design environments.

- Synopsys (FPGA Compiler, FPGA Express)
- Exemplar (Spectrum)
- Synplicity (Synplify)

For schematic design entry, the Xilinx FPGA Foundation and alliance development system provides interfaces to the following schematic-capture design environments.

- Mentor Graphics V8 (Design Architect, QuickSim II)
- Viewlogic Systems (Viewdraw)

Third-party vendors support many other environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Virtex FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The "soft macro" portion of the library contains detailed descriptions of common logic functions, but does not contain any partitioning or placement information. The performance of these macros depends, therefore, on the partitioning and placement obtained during implementation.

RPMs, on the other hand, do contain predetermined partitioning and placement information that permits optimal implementation of these functions. Users can create their own library of soft macros or RPMs based on the macros and primitives in the standard library.

The design environment supports hierarchical design entry, with high-level schematics that comprise major functional blocks, while lower-level schematics define the logic in these blocks. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical

design, thus allowing the most convenient entry method to be used for each portion of the design.

Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF net list for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floor planning.

The implementation software incorporates Timing Wizard® timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered on a schematic in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the net list for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the TRACE® static timing analyzer.

For in-circuit debugging, the development system includes a download and readback cable. This cable connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can single-step the logic, readback the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.



- At the rising edge of CCLK: If BUSY is Low, the data is accepted on this clock. If BUSY is High (from a previous write), the data is not accepted. Acceptance will instead occur on the first clock after BUSY goes Low, and the data must be held until this has happened.
- 4. Repeat steps 2 and 3 until all the data has been sent.
- 5. De-assert $\overline{\text{CS}}$ and $\overline{\text{WRITE}}$.

A flowchart for the write operation appears in Figure 17. Note that if CCLK is slower than f_{CCNH} , the FPGA never asserts BUSY. In this case, the above handshake is unnecessary, and data can simply be entered into the FPGA every CCLK cycle.

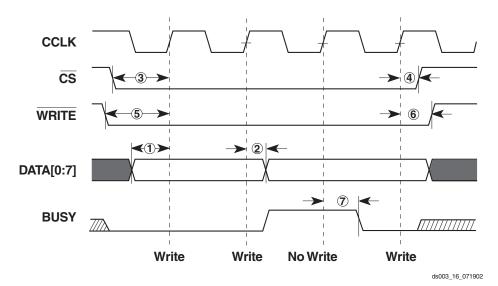


Figure 16: Write Operations

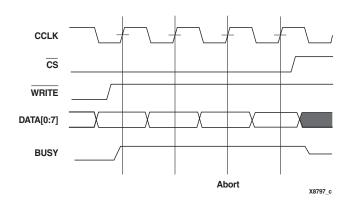


Figure 18: SelectMAP Write Abort Waveforms

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the PROGRAM pin must be pulled High prior to reconfiguration. A Low on the PROGRAM pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the CFG_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

- Load the CFG_IN instruction into the boundary-scan instruction register (IR)
- 2. Enter the Shift-DR (SDR) state
- 3. Shift a configuration bitstream into TDI
- 4. Return to Run-Test-Idle (RTI)
- 5. Load the JSTART instruction into IR
- 6. Enter the SDR state
- 7. Clock TCK through the startup sequence
- 8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting $\overline{\mathsf{PROGRAM}}$.

The end of the memory-clearing phase is signalled by INIT going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

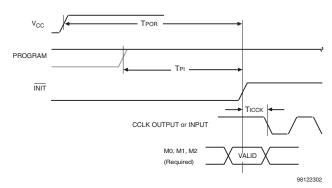


Figure 19: Power-Up Timing Configuration Signals

Table 10: Power-up Timing Characteristics

| Description | Symbol | Value | Units |
|---------------------|----------------------|-------|---------|
| Power-on Reset | T _{POR} | 2.0 | ms, max |
| Program Latency | T _{PL} | 100.0 | μs, max |
| CCLK (output) Delay | T _{ICCK} | 0.5 | μs, min |
| | | 4.0 | μs, max |
| Program Pulse Width | T _{PROGRAM} | 300 | ns, min |

Delaying Configuration

INIT can be held Low using an open-drain driver. An open-drain is required since INIT is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.



Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 "Virtex Configuration Architecture Advanced Users Guide".

Table 11: Virtex Bit-Stream Lengths

| Device | # of Configuration Bits |
|---------|-------------------------|
| XCV50 | 559,200 |
| XCV100 | 781,216 |
| XCV150 | 1,040,096 |
| XCV200 | 1,335,840 |
| XCV300 | 1,751,808 |
| XCV400 | 2,546,048 |
| XCV600 | 3,607,968 |
| XCV800 | 4,715,616 |
| XCV1000 | 6,127,744 |

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

| Date | Version | Revision |
|-------|---------|--|
| 11/98 | 1.0 | Initial Xilinx release. |
| 01/99 | 1.2 | Updated package drawings and specs. |
| 02/99 | 1.3 | Update of package drawings, updated specifications. |
| 05/99 | 1.4 | Addition of package drawings and specifications. |
| 05/99 | 1.5 | Replaced FG 676 & FG680 package drawings. |
| 07/99 | 1.6 | Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments. |
| 09/99 | 1.7 | Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} . |
| 01/00 | 1.8 | Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43. |



Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device operation. The actual current consumed depends on the power-on ramp rate of the power supply. This is the time required to reach the nominal power supply voltage of the device⁽¹⁾ from 0 V. The current is highest at the fastest suggested ramp rate (0 V to nominal voltage in 2 ms) and is lowest at the slowest allowed ramp rate (0 V to nominal voltage in 50 ms). For more details on power supply requirements, see Application Note XAPP158 on www.xilinx.com.

| Product | Description ⁽²⁾ | Current Requirement ^(1,3) | | |
|---------------------------------|---------------------------------|--------------------------------------|--|--|
| Virtex Family, Commercial Grade | Minimum required current supply | 500 mA | | |
| Virtex Family, Industrial Grade | Minimum required current supply | 2 A | | |

Notes:

- Ramp rate used for this specification is from 0 2.7 VDC. Peak current occurs on or near the internal power-on reset threshold of 1.0V and lasts for less than 3 ms.
- Devices are guaranteed to initialize properly with the minimum current available from the power supply as noted above.
- 3. Larger currents can result if ramp rates are forced to be faster.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed output currents over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at minimum V_{CCO} for each standard with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

| Input/Output | | V _{IL} | V _{IH} | | V _{OL} | V _{OH} | I _{OL} | I _{OH} |
|-----------------------|--------|-------------------------|-------------------------|------------------------|-------------------------|-------------------------|-----------------|-----------------|
| Standard | V, min | V, max | V, min | V, max | V, Max | V, Min | mA | mA |
| LVTTL ⁽¹⁾ | - 0.5 | 0.8 | 2.0 | 5.5 | 0.4 | 2.4 | 24 | -24 |
| LVCMOS2 | - 0.5 | .7 | 1.7 | 5.5 | 0.4 | 1.9 | 12 | -12 |
| PCI, 3.3 V | - 0.5 | 44% V _{CCINT} | 60% V _{CCINT} | V _{CCO} + 0.5 | 10% V _{CCO} | 90% V _{CCO} | Note 2 | Note 2 |
| PCI, 5.0 V | - 0.5 | 0.8 | 2.0 | 5.5 | 0.55 | 2.4 | Note 2 | Note 2 |
| GTL | - 0.5 | V _{REF} - 0.05 | V _{REF} + 0.05 | 3.6 | 0.4 | n/a | 40 | n/a |
| GTL+ | - 0.5 | V _{REF} – 0.1 | V _{REF} + 0.1 | 3.6 | 0.6 | n/a | 36 | n/a |
| HSTL I ⁽³⁾ | - 0.5 | V _{REF} – 0.1 | V _{REF} + 0.1 | 3.6 | 0.4 | V _{CCO} - 0.4 | 8 | -8 |
| HSTL III | - 0.5 | V _{REF} – 0.1 | V _{REF} + 0.1 | 3.6 | 0.4 | V _{CCO} - 0.4 | 24 | -8 |
| HSTL IV | - 0.5 | V _{REF} – 0.1 | V _{REF} + 0.1 | 3.6 | 0.4 | V _{CCO} - 0.4 | 48 | -8 |
| SSTL3 I | - 0.5 | V _{REF} - 0.2 | V _{REF} + 0.2 | 3.6 | V _{REF} - 0.6 | V _{REF} + 0.6 | 8 | -8 |
| SSTL3 II | - 0.5 | V _{REF} - 0.2 | V _{REF} + 0.2 | 3.6 | V _{REF} - 0.8 | V _{REF} + 0.8 | 16 | -16 |
| SSTL2 I | - 0.5 | V _{REF} - 0.2 | V _{REF} + 0.2 | 3.6 | V _{REF} - 0.61 | V _{REF} + 0.61 | 7.6 | -7.6 |
| SSTL2 II | - 0.5 | V _{REF} - 0.2 | V _{REF} + 0.2 | 3.6 | V _{REF} - 0.80 | V _{REF} + 0.80 | 15.2 | -15.2 |
| CTT | - 0.5 | V _{REF} - 0.2 | V _{REF} + 0.2 | 3.6 | V _{REF} - 0.4 | V _{REF} + 0.4 | 8 | -8 |
| AGP | - 0.5 | V _{REF} - 0.2 | V _{REF} + 0.2 | 3.6 | 10% V _{CCO} | 90% V _{CCO} | Note 2 | Note 2 |

Notes:

- V_{OL} and V_{OH} for lower drive currents are sample tested.
- 2. Tested according to the relevant specifications.
- DC input and output levels for HSTL18 (HSTL I/O standard with V_{CCO} of 1.8 V) are provided in an HSTL white paper on www.xilinx.com.



Virtex Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex devices unless otherwise noted.

IOB Input Switching Characteristics

Input delays associated with the pad are specified for LVTTL levels. For other standards, adjust the delays with the values shown in , page 6.

| | | | | Speed | Grade | | |
|--|---------|---------------------|------|-------|-------|-----|---------|
| Description | Device | Symbol | Min | -6 | -5 | -4 | Units |
| Propagation Delays | | | | | | | |
| Pad to I output, no delay | All | T _{IOPI} | 0.39 | 0.8 | 0.9 | 1.0 | ns, max |
| Pad to I output, with delay | XCV50 | T _{IOPID} | 0.8 | 1.5 | 1.7 | 1.9 | ns, max |
| | XCV100 | | 0.8 | 1.5 | 1.7 | 1.9 | ns, max |
| | XCV150 | | 0.8 | 1.5 | 1.7 | 1.9 | ns, max |
| | XCV200 | | 0.8 | 1.5 | 1.7 | 1.9 | ns, max |
| | XCV300 | | 0.8 | 1.5 | 1.7 | 1.9 | ns, max |
| | XCV400 | | 0.9 | 1.8 | 2.0 | 2.3 | ns, max |
| | XCV600 | | 0.9 | 1.8 | 2.0 | 2.3 | ns, max |
| | XCV800 | | 1.1 | 2.1 | 2.4 | 2.7 | ns, max |
| | XCV1000 | | 1.1 | 2.1 | 2.4 | 2.7 | ns, max |
| Pad to output IQ via transparent latch, no delay | All | T _{IOPLI} | 0.8 | 1.6 | 1.8 | 2.0 | ns, max |
| Pad to output IQ via transparent | XCV50 | T _{IOPLID} | 1.9 | 3.7 | 4.2 | 4.8 | ns, max |
| latch, with delay | XCV100 | | 1.9 | 3.7 | 4.2 | 4.8 | ns, max |
| | XCV150 | | 2.0 | 3.9 | 4.3 | 4.9 | ns, max |
| | XCV200 | | 2.0 | 4.0 | 4.4 | 5.1 | ns, max |
| | XCV300 | | 2.0 | 4.0 | 4.4 | 5.1 | ns, max |
| | XCV400 | | 2.1 | 4.1 | 4.6 | 5.3 | ns, max |
| | XCV600 | | 2.1 | 4.2 | 4.7 | 5.4 | ns, max |
| | XCV800 | | 2.2 | 4.4 | 4.9 | 5.6 | ns, max |
| | XCV1000 | | 2.3 | 4.5 | 5.1 | 5.8 | ns, max |
| Sequential Delays | | | · | | | | |
| Clock CLK | All | | | | | | |
| Minimum Pulse Width, High | | T _{CH} | 0.8 | 1.5 | 1.7 | 2.0 | ns, min |
| Minimum Pulse Width, Low | | T _{CL} | 0.8 | 1.5 | 1.7 | 2.0 | ns, min |
| Clock CLK to output IQ | | T _{IOCKIQ} | 0.2 | 0.7 | 0.7 | 8.0 | ns, max |



IOB Input Switching Characteristics Standard Adjustments

| | | | Speed Grade | | | | |
|------------------------------------|-----------------------|-------------------------|-------------|-------|-------|-------|-------|
| Description | Symbol | Standard ⁽¹⁾ | Min | -6 | -5 | -4 | Units |
| Data Input Delay Adjustments | | | | | | | |
| Standard-specific data input delay | T _{ILVTTL} | LVTTL | 0 | 0 | 0 | 0 | ns |
| adjustments | T _{ILVCMOS2} | LVCMOS2 | -0.02 | -0.04 | -0.04 | -0.05 | ns |
| | T _{IPCI33_3} | PCI, 33 MHz, 3.3 V | -0.05 | -0.11 | -0.12 | -0.14 | ns |
| | T _{IPCI33_5} | PCI, 33 MHz, 5.0 V | 0.13 | 0.25 | 0.28 | 0.33 | ns |
| | T _{IPCI66_3} | PCI, 66 MHz, 3.3 V | -0.05 | -0.11 | -0.12 | -0.14 | ns |
| | T _{IGTL} | GTL | 0.10 | 0.20 | 0.23 | 0.26 | ns |
| | T _{IGTLP} | GTL+ | 0.06 | 0.11 | 0.12 | 0.14 | ns |
| | T _{IHSTL} | HSTL | 0.02 | 0.03 | 0.03 | 0.04 | ns |
| | T _{ISSTL2} | SSTL2 | -0.04 | -0.08 | -0.09 | -0.10 | ns |
| | T _{ISSTL3} | SSTL3 | -0.02 | -0.04 | -0.05 | -0.06 | ns |
| | T _{ICTT} | CTT | 0.01 | 0.02 | 0.02 | 0.02 | ns |
| | T _{IAGP} | AGP | -0.03 | -0.06 | -0.07 | -0.08 | ns |

Notes:

IOB Output Switching Characteristics

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays with the values shown in **IOB Output Switching Characteristics Standard Adjustments**, page 9.

| | | Speed Grade | | | | |
|--|----------------------|-------------|-----|-----|-----|---------|
| Description | Symbol | Min | -6 | -5 | -4 | Units |
| Propagation Delays | | | | | | |
| O input to Pad | T _{IOOP} | 1.2 | 2.9 | 3.2 | 3.5 | ns, max |
| O input to Pad via transparent latch | T _{IOOLP} | 1.4 | 3.4 | 3.7 | 4.0 | ns, max |
| 3-State Delays | | · | | | | |
| T input to Pad high-impedance ⁽¹⁾ | T _{IOTHZ} | 1.0 | 2.0 | 2.2 | 2.4 | ns, max |
| T input to valid data on Pad | T _{IOTON} | 1.4 | 3.1 | 3.3 | 3.7 | ns, max |
| T input to Pad high-impedance via transparent latch ⁽¹⁾ | T _{IOTLPHZ} | 1.2 | 2.4 | 2.6 | 3.0 | ns, max |
| T input to valid data on Pad via transparent latch | T _{IOTLPON} | 1.6 | 3.5 | 3.8 | 4.2 | ns, max |
| GTS to Pad high impedance ⁽¹⁾ | T _{GTS} | 2.5 | 4.9 | 5.5 | 6.3 | ns, max |
| Sequential Delays | | | 1 | 1 | | , |
| Clock CLK | | | | | | |
| Minimum Pulse Width, High | T _{CH} | 0.8 | 1.5 | 1.7 | 2.0 | ns, min |
| Minimum Pulse Width, Low | T _{CL} | 0.8 | 1.5 | 1.7 | 2.0 | ns, min |

^{1.} Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see Table 3.



| | | Speed Grade | | | | |
|---|--|-------------|---------|-------------|---------|---------|
| Description | Symbol | Min | -6 | -5 | -4 | Units |
| Clock CLK to Pad delay with OBUFT enabled (non-3-state) | T _{IOCKP} | 1.0 | 2.9 | 3.2 | 3.5 | ns, max |
| Clock CLK to Pad high-impedance (synchronous) ⁽¹⁾ | T _{IOCKHZ} | 1.1 | 2.3 | 2.5 | 2.9 | ns, max |
| Clock CLK to valid data on Pad delay, plus enable delay for OBUFT | T _{IOCKON} | 1.5 | 3.4 | 3.7 | 4.1 | ns, max |
| Setup and Hold Times before/after Clock | CLK ⁽²⁾ | | Setup | Time / Hold | Time | 1 |
| O input | T _{IOOCK} /T _{IOCKO} | 0.51 / 0 | 1.1 / 0 | 1.2 / 0 | 1.3 / 0 | ns, min |
| OCE input | T _{IOOCECK} /T _{IOCKOCE} | 0.37 / 0 | 0.8 / 0 | 0.9 / 0 | 1.0 / 0 | ns, min |
| SR input (OFF) | T _{IOSRCKO} /T _{IOCKOSR} | 0.52 / 0 | 1.1 / 0 | 1.2 / 0 | 1.4 / 0 | ns, min |
| 3-State Setup Times, T input | T _{IOTCK} /T _{IOCKT} | 0.34 / 0 | 0.7 / 0 | 0.8 / 0 | 0.9 / 0 | ns, min |
| 3-State Setup Times, TCE input | T _{IOTCECK} /T _{IOCKTCE} | 0.41 / 0 | 0.9 / 0 | 0.9 / 0 | 1.1 / 0 | ns, min |
| 3-State Setup Times, SR input (TFF) | T _{IOSRCKT} /T _{IOCKTSR} | 0.49 / 0 | 1.0 / 0 | 1.1 / 0 | 1.3 / 0 | ns, min |
| Set/Reset Delays | | | | | | |
| SR input to Pad (asynchronous) | T _{IOSRP} | 1.6 | 3.8 | 4.1 | 4.6 | ns, max |
| SR input to Pad high-impedance (asynchronous) ⁽¹⁾ | T _{IOSRHZ} | 1.6 | 3.1 | 3.4 | 3.9 | ns, max |
| SR input to valid data on Pad (asynchronous) | T _{IOSRON} | 2.0 | 4.2 | 4.6 | 5.1 | ns, max |
| GSR to Pad | T _{IOGSRQ} | 4.9 | 9.7 | 10.9 | 12.5 | ns, max |

Notes:

- 1. 3-state turn-off delays should not be adjusted.
- 2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Clock Distribution Guidelines

| | | | Speed Grade | | | |
|--|---------|-----------------------|-------------|------|------|---------|
| Description | Device | Symbol | -6 | -5 | -4 | Units |
| Global Clock Skew ⁽¹⁾ | | | | | | |
| Global Clock Skew between IOB Flip-flops | XCV50 | T _{GSKEWIOB} | 0.10 | 0.12 | 0.14 | ns, max |
| | XCV100 | | 0.12 | 0.13 | 0.15 | ns, max |
| | XCV150 | | 0.12 | 0.13 | 0.15 | ns, max |
| | XCV200 | | 0.13 | 0.14 | 0.16 | ns, max |
| | XCV300 | | 0.14 | 0.16 | 0.18 | ns, max |
| | XCV400 | | 0.13 | 0.13 | 0.14 | ns, max |
| | XCV600 | | 0.14 | 0.15 | 0.17 | ns, max |
| | XCV800 | | 0.16 | 0.17 | 0.20 | ns, max |
| | XCV1000 | | 0.20 | 0.23 | 0.25 | ns, max |

Notes:

Clock Distribution Switching Characteristics

| | | Speed Grade | | | | |
|---|-------------------|-------------|-----|------------|-----|---------|
| Description | Symbol | Min | -6 | - 5 | -4 | Units |
| GCLK IOB and Buffer | | | | | | |
| Global Clock PAD to output. | T _{GPIO} | 0.33 | 0.7 | 0.8 | 0.9 | ns, max |
| Global Clock Buffer I input to O output | T _{GIO} | 0.34 | 0.7 | 0.8 | 0.9 | ns, max |

^{1.} These clock-skew delays are provided for guidance only. They reflect the delays encountered in a typical design under worst-case conditions. Precise values for a particular design are provided by the timing analyzer.

Product Obsolete/Under Obsolescence







Virtex Pinout Information

Pinout Tables

See www.xilinx.com for updates or additional pinout information. For convenience, Table 2, Table 3 and Table 4 list the locations of special-purpose and power-supply pins. Pins not listed are either user I/Os or not connected, depending on the device/package combination. See the Pinout Diagrams starting on page 17 for any pins not listed for a particular part/package combination.

Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages)

| Pin Name | Device | CS144 | TQ144 | PQ/HQ240 |
|--------------------|--------|------------------------------------|------------------------------------|---|
| GCK0 | All | K7 | 90 | 92 |
| GCK1 | All | M7 | 93 | 89 |
| GCK2 | All | A7 | 19 | 210 |
| GCK3 | All | A6 | 16 | 213 |
| MO | All | M1 | 110 | 60 |
| M1 | All | L2 | 112 | 58 |
| M2 | All | N2 | 108 | 62 |
| CCLK | All | B13 | 38 | 179 |
| PROGRAM | All | L12 | 72 | 122 |
| DONE | All | M12 | 74 | 120 |
| INIT | All | L13 | 71 | 123 |
| BUSY/DOUT | All | C11 | 39 | 178 |
| D0/DIN | All | C12 | 40 | 177 |
| D1 | All | E10 | 45 | 167 |
| D2 | All | E12 | 47 | 163 |
| D3 | All | F11 | 51 | 156 |
| D4 | All | H12 | 59 | 145 |
| D5 | All | J13 | 63 | 138 |
| D6 | All | J11 | 65 | 134 |
| D7 | All | K10 | 70 | 124 |
| WRITE | All | C10 | 32 | 185 |
| CS | All | D10 | 33 | 184 |
| TDI | All | A11 | 34 | 183 |
| TDO | All | A12 | 36 | 181 |
| TMS | All | B1 | 143 | 2 |
| TCK | All | C3 | 2 | 239 |
| V _{CCINT} | All | A9, B6, C5, G3, G12, M5, M9, N6 | 10, 15, 25, 57, 84, 94, 99, 126 | 16, 32, 43, 77, 88, 104, 137, 148, 164, 198, 214, 225 |



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

| Pin Name | Device | CS144 | TQ144 | PQ/HQ240 |
|--|------------|---|---|--|
| V _{CCO} | All | Banks 0 and 1: A2, A13, D7 Banks 2 and 3: B12, G11, M13 Banks 4 and 5: N1, N7, N13 Banks 6 and 7: B2, G2, M2 | No I/O Banks in this package: 1, 17, 37, 55, 73, 92, 109, 128 | No I/O Banks in this package: 15, 30, 44, 61, 76, 90, 105, 121, 136, 150, 165, 180, 197, 212, 226, 240 |
| V _{RFF} Bank 0 | XCV50 | C4, D6 | 5, 13 | 218, 232 |
| (V _{REF} pins are listed | XCV100/150 | + B4 | + 7 | + 229 |
| incrementally. Connect | XCV200/300 | N/A | N/A | + 236 |
| all pins listed for both the required device | XCV400 | N/A | N/A | + 215 |
| and all smaller devices | XCV600 | N/A | N/A | + 230 |
| listed in the same package.) | XCV800 | N/A | N/A | + 222 |
| Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O. | | | | |
| V _{REF} , Bank 1 | XCV50 | A10, B8 | 22, 30 | 191, 205 |
| (V _{REF} pins are listed | XCV100/150 | + D9 | + 28 | + 194 |
| incrementally. Connect all pins listed for both | XCV200/300 | N/A | N/A | + 187 |
| the required device | XCV400 | N/A | N/A | + 208 |
| and all smaller devices listed in the same | XCV600 | N/A | N/A | + 193 |
| package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O. | XCV800 | N/A | N/A | + 201 |
| V _{REF} , Bank 2 | XCV50 | D11, F10 | 42, 50 | 157, 171 |
| (V _{REF} pins are listed | XCV100/150 | + D13 | + 44 | + 168 |
| incrementally. Connect all pins listed for both | XCV200/300 | N/A | N/A | + 175 |
| the required device and all smaller devices listed in the same | XCV400 | N/A | N/A | + 154 |
| | XCV600 | N/A | N/A | + 169 |
| package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O. | XCV800 | N/A | N/A | + 161 |



Table 3: Virtex Pinout Tables (BGA) (Continued)

| Pin Name | Device | BG256 | BG352 | BG432 | BG560 |
|---|------------|--|--|--|---|
| V _{REF} , Bank 7 | XCV50 | G3, H1 | N/A | N/A | N/A |
| (V _{REF} pins are listed | XCV100/150 | + D1 | D26, G26, | N/A | N/A |
| incrementally. Connect all pins listed for both the | | | L26 | | |
| required device and all | XCV200/300 | + B2 | + E24 | F28, F31, | N/A |
| smaller devices listed in the same package.) | | | | J30, N30 | |
| Within each bank, if input reference voltage is not required, all V _{REF} pins are | XCV400 | N/A | N/A | + R31 | E31, G31, K31, P31, T31 |
| general I/O. | XCV600 | N/A | N/A | + J28 | + H32 |
| | XCV800 | N/A | N/A | + M28 | + L33 |
| | XCV1000 | N/A | N/A | N/A | + D31 |
| GND | All | C3, C18, D4, D5, D9, D10, D11, D12, D16, D17, E4, E17, J4, J17, K4, K17, L4, L17, M4, M17, T4, T17, U4, U5, U9, U10, U11, U12, U16, U17, V3, V18 | A1, A2, A5, A8, A14, A19, A22, A25, A26, B1, B26, E1, E26, H1, H26, N1, P26, W1, W26, AB1, AB26, AE1, AF2, AF5, AF8, AF13, AF19, AF22, AF25, AF26 | A2, A3, A7, A9, A14, A18, A23, A25, A29, A30, B1, B2, B30, B31, C1, C31, D16, G1, G31, J1, J31, P1, P31, T4, T28, V1, V31, AC1, AC31, AE1, AE31, AH16, AJ1, AJ31, AK1, AK2, AK30, AK31, AL2, AL3, AL7, AL9 AL14, AL18 AL23, AL25, AL29, AL30 | A1, A7, A12, A14, A18, A20, A24, A29, A32, A33, B1, B6, B9, B15, B23, B27, B31, C2, E1, F32, G2, G33, J32, K1, L2, M33, P1, P33, R32, T1, V33, W2, Y1, Y33, AB1, AC32, AD33, AE2, AG1, AG32, AH2, AJ33, AL32, AM3, AM7, AM11, AM19, AM25, AM28, AM33, AN1, AN2, AN5, AN10, AN14, AN16, AN20, AN22, AN27, AN33 |
| GND ⁽¹⁾ | All | J9, J10, J11, J12, K9, K10, K11, K12, L9, L10, L11, L12, M9, M10, M11, M12 | N/A | N/A | N/A |
| No Connect | All | N/A | N/A | N/A | C31, AC2, AK4, AL3 |

Notes:

1. 16 extra balls (grounded) at package center.

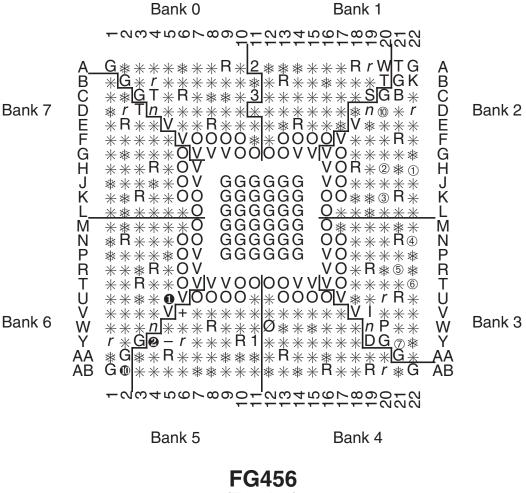


Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

| Pin Name | Device | FG256 | FG456 | FG676 | FG680 |
|--|--------|-------|---|---|-------|
| No Connect (No-connect pins are listed incrementally. All pins listed for both the required device and all larger devices listed in the same package are no connects.) | XCV800 | N/A | N/A | A2, A3, A15, A25, B1, B6, B11, B16, B21, B24, B26, C1, C2, C25, C26, F2, F6, F21, F25, L2, L25, N25, P2, T2, T25, AA2, AA6, AA21, AA25, AD1, AD2, AD25, AE1, AE3, AE6, AE11, AE14, AE16, AE21, AE24, AE26, AF2, AF24, AF25 | N/A |
| | XCV600 | N/A | N/A | same as above | N/A |
| | XCV400 | N/A | N/A | + A9, A10, A13, A16, A24, AC1, AC25, AE12, AE15, AF3, AF10, AF11, AF13, AF14, AF16, AF18, AF23, B4, B12, B13, B15, B17, D1, D25, H26, J1, K26, L1, M1, M25, N1, N26, P1, P26, R2, R26, T1, T26, U26, V1 | N/A |
| | XCV300 | N/A | D4, D19, W4, W19 | N/A | N/A |
| | XCV200 | N/A | + A2, A6, A12, B11, B16, C2, D1, D18, E17, E19, G2, G22, L2, L19, M2, M21, R3, R20, U3, U18, Y22, AA1, AA3, AA11, AA16, AB7, AB12, AB21, | N/A | N/A |
| | XCV150 | N/A | + A13, A14, C8, C9, E13, F11, H21, J1, J4, K2, K18, K19, M17, N1, P1, P5, P22, R22, W13, W15, AA9, AA10, AB8, AB14 | N/A | N/A |



FG456 Pin Function Diagram



(Top view)

Figure 9: FG456 Pin Function Diagram

Notes:

Packages FG456 and FG676 are layout compatible.



FG676 Pin Function Diagram

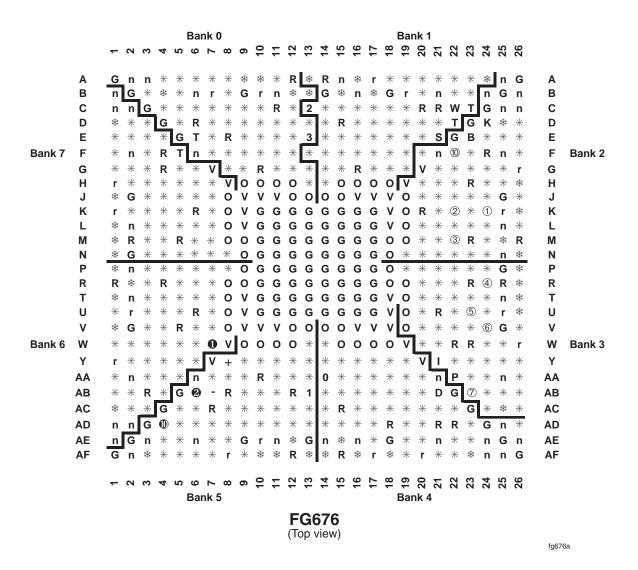


Figure 10: FG676 Pin Function Diagram

Notes:

Packages FG456 and FG676 are layout compatible.



Revision History

| Date | Version | Revision |
|-------------|---------|--|
| 11/98 | 1.0 | Initial Xilinx release. |
| 01/99-02/99 | 1.2-1.3 | Both versions updated package drawings and specs. |
| 05/99 | 1.4 | Addition of package drawings and specifications. |
| 05/99 | 1.5 | Replaced FG 676 & FG680 package drawings. |
| 07/99 | 1.6 | Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments. |
| 09/99 | 1.7 | Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} . |
| 01/00 | 1.8 | Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43. |
| 01/00 | 1.9 | Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes. |
| 03/00 | 2.0 | New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration. |
| 05/00 | 2.1 | Modified "Pins not listed" statement. Speed grade update to Final status. |
| 05/00 | 2.2 | Modified Table 18. |
| 09/00 | 2.3 | Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics. |
| 10/00 | 2.4 | Corrected pinout info for devices in the BG256, BG432, and BG560 pkgs in Table 18. Corrected BG256 Pin Function Diagram. |
| 04/02/01 | 2.5 | Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL. Converted file to modularized format. See section Virtex Data Sheet, below. |
| 04/19/01 | 2.6 | Corrected pinout information for FG676 device in Table 4. (Added AB22 pin.) |
| 07/19/01 | 2.7 | Clarified V_{CCINT} pinout information and added AE19 pin for BG352 devices in Table 3. Changed pinouts listed for BG352 XCV400 devices in banks 0 thru 7. |
| 07/19/02 | 2.8 | Changed pinouts listed for GND in TQ144 devices (see Table 2). |
| 03/01/13 | 4.0 | The products listed in this data sheet are obsolete. See XCN10016 for further information. |

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs:
 DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)